

# Device Reliability Prediction

Case 1 - Black Box Estimates (50% Stress, Temp. = 40 Deg. C, No Device burn-in)

**Date:** 1/25/19

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**Unit:** LMZ14203H

**Manufacturer:** Texas Instruments Inc.

<i>Device Type</i>	<i>Qty</i>	<i>Failure Rate</i>	<i>Quality Factor</i>	<i>Total Device Failure Rate</i>
Capacitor, Fixed, Ceramic	3	1	1	3
Inductor, Power Filter	1	19	1	19
IC, Analog	1	1.8	1	1.8
<b><i>Total FIT Rate:</i></b>				23.8
<b><i>Equivalent MTBF (hrs):</i></b>				42,016,807